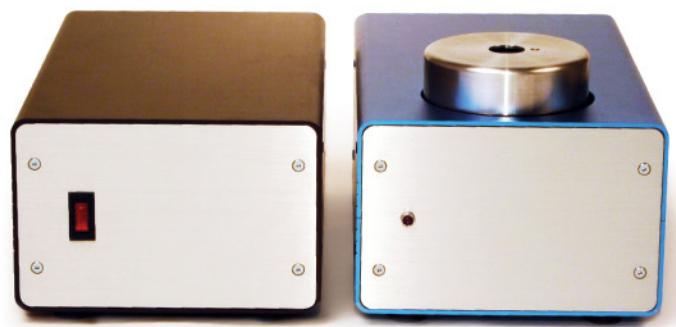


Atomic Force Microscope(AFM/SPM) ❖❖❖❖❖



BASO AFM/SPM

Features:

- Innovative: A novel optical astigmatism technique
- Convenient: Extremely easy to use in one system!
- Flexible: LabVIEW software makes easy expansion
- Modularization: Easy to change modules to get different signals you want.
- Passive isolation is integrated.

Specification

AFM function

operation mode	contact mode, oscillation mode
detecting principle	optical astigmatism
image resolution	256 x 256 pixel
contact mode force curve	YES
oscillation mode force curve	YES
raw data export	YES
automatic probe approach	YES
automatic probe alignment	YES
probe orientation adjustment	YES

Scanner (X/Y/Z)

scanning range	20 μm / 20 μm / 4 μm
open loop resolution	1 nm / 1 nm / 0.2 nm

Sample

maximum size	diameter 50mm x thickness 5 mm
maximum weight	100 g

Electronics

External AD channel	1
AD resolution	16 bit
sampling rate	100 kHz
embedded feedback controller	PI-control

Misc

passive vibration isolator	YES
power rating	110V / 60Hz / 50 W